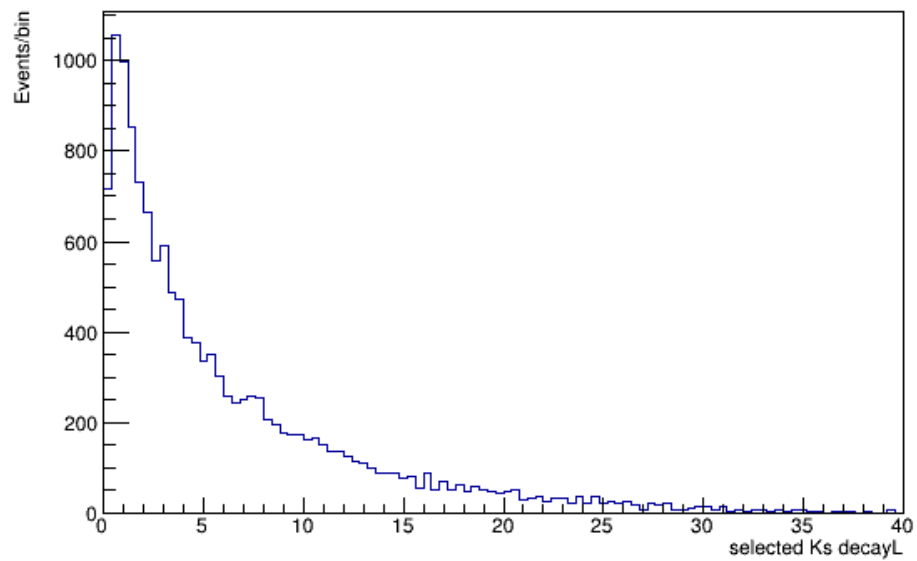
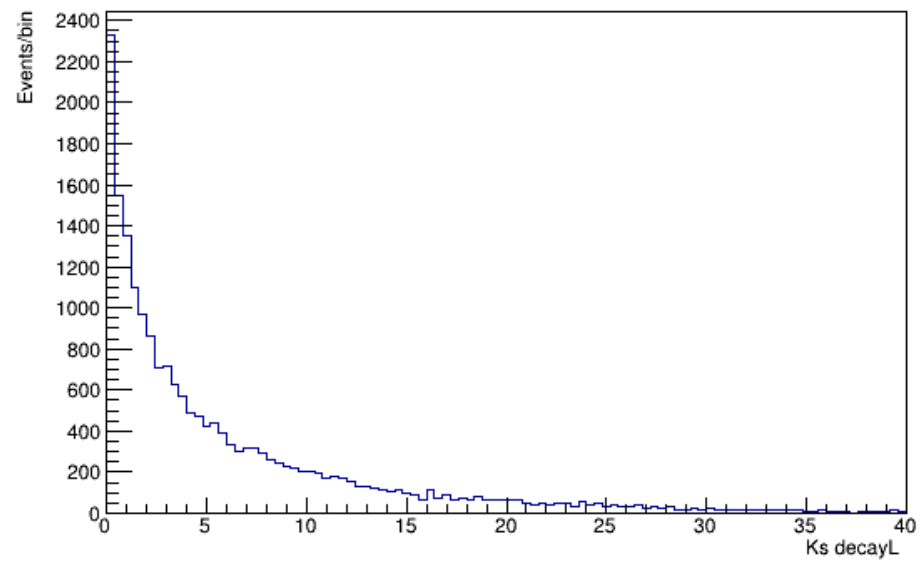


$K_s \text{ eff}$

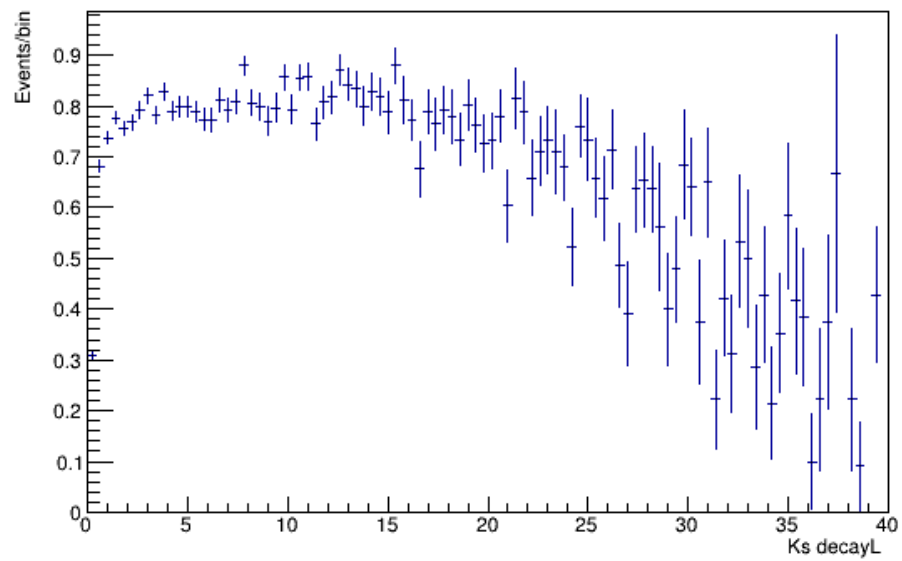
selected_decayL



truth_decayL



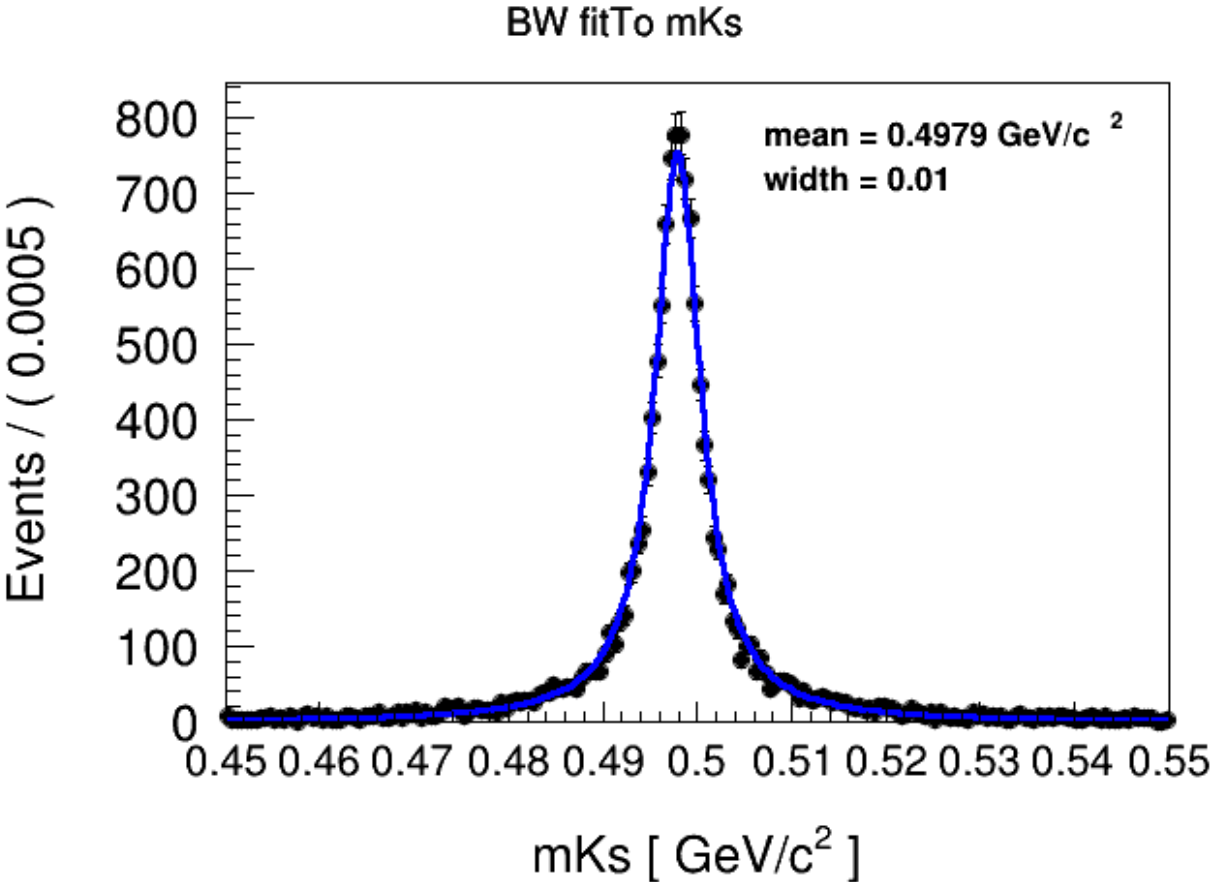
Eff



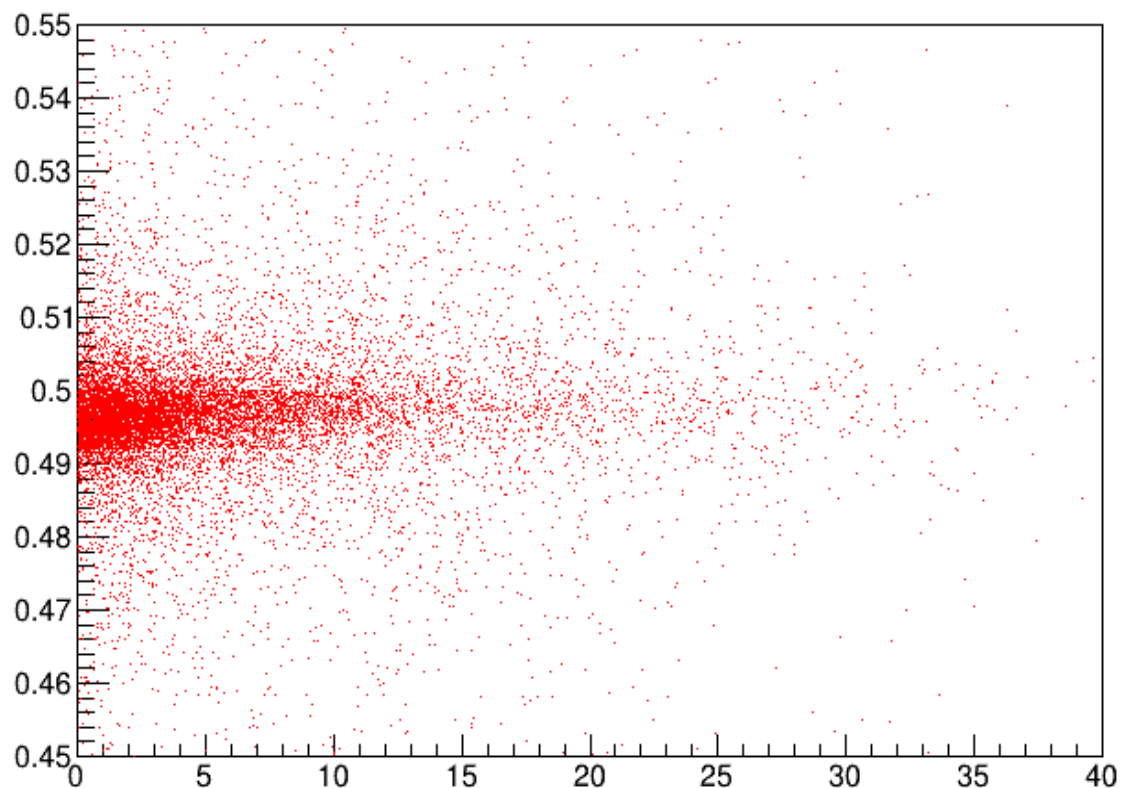
编号	带电径迹数	原因	事例数	占比
0	---	正确重建（如有多个候选，保留最接近中心质量事例）	14094	70%
1	---	带电径迹小于两条	3040	15%
2	2	两条相同电荷径迹	153	1%
3	2	$\text{abs}(mKs-0.0.497611)>0.2$	112	1%
4	2	第一次拟合失败	248	1%
5	2	第二次拟合失败	172	1%
6	2	$\text{chi}2>200$	123	1%
7	2	$\text{decayL}/\text{err}\leq 2$	1573	8%
8	2	$\text{fabs}(\text{costheta}) \geq 0.93$	180	1%
9	2	$(*\text{itTrk})\rightarrow\text{isMdcKalTrackValid}()$	8	0%
10	>2	有多种失败组合	297	1%
		合计	20000	100%

其中带电径迹小于2条时，前100个事例中，有41个事例存在明显径迹，但未被正确重建。

mKs fit



mKs with respected to decayL



```

*****
*      Row      * truth_dec *      mKs *      fmKs *
*****
*      1 * 1.7676374 * 0.4975067 * 0.4975067 *
*      2 * 4.9012351 * 0.4950918 * 0.4950918 *
*      3 * 3.5560896 * 0.5011036 * 0.5011036 *
*      5 * 1.2432871 * 0.4930084 * 0.4930084 *
*      6 * 8.1509947 * 0.4932067 * 0.4932067 *
*      7 * 0.1757787 * 0.4957480 * 0.4957480 *
*      8 * 14.382088 * 0.5196535 * 0.5196535 *
*     10 * 0.9788663 * 0.4953511 * 0.4953511 *
*     11 * 1.3289038 * 0.4967906 * 0.4967906 *
*     12 * 4.3401912 * 0.5001854 * 0.5001854 *
*     13 * 2.4483018 * 0.4977303 * 0.4977303 *
*     16 * 1.4312060 * 0.4988122 * 0.4988122 *
*     17 * 1.7537608 * 0.4952633 * 0.4952633 *
*     19 * 0.2682587 * 0.5166199 * 0.5166199 *
*     20 * 0.4547329 * 0.4952275 * 0.4952275 *
*     21 * 2.7933343 * 0.4917490 * 0.4917490 *
*     22 * 3.2698234 * 0.4924635 * 0.4924635 *
*     24 * 10.156250 * 0.4957654 * 0.4957654 *
*     25 * 3.8510151 * 0.4978406 * 0.4978406 *
*     26 * 9.3015311 * 0.4909686 * 0.4909686 *
*     27 * 1.2628998 * 0.4969977 * 0.4969977 *
*     30 * 0.9353219 * 0.4120814 * 0.4120814 *
*     31 * 21.020005 * 0.4894546 * 0.4894546 *
*     32 * 14.176639 * 0.4787167 * 0.4787167 *
*     33 * 3.0785813 * 0.4964129 * 0.4964129 *
*****

```

mKs with respected to PKs

